

FIG.1A

Title: AN INTEGRATED ELECTROMIGRATION LENGTH EFFECT TESTING METHOD AND APPARATUS

Filed: February 22, 2002

Inventor: Wei Zhang

Docket No.: SUN-P6557

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ress mail: ET533056828US

Attorney: Timothy A. Brisson

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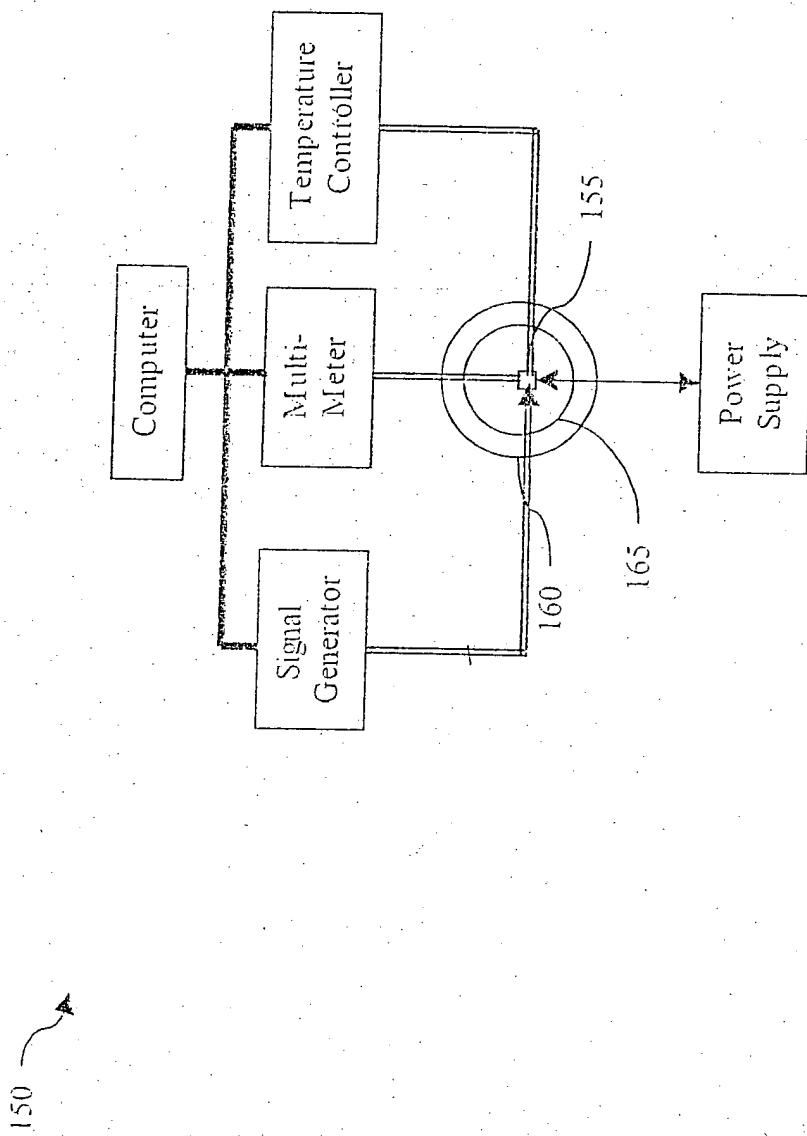
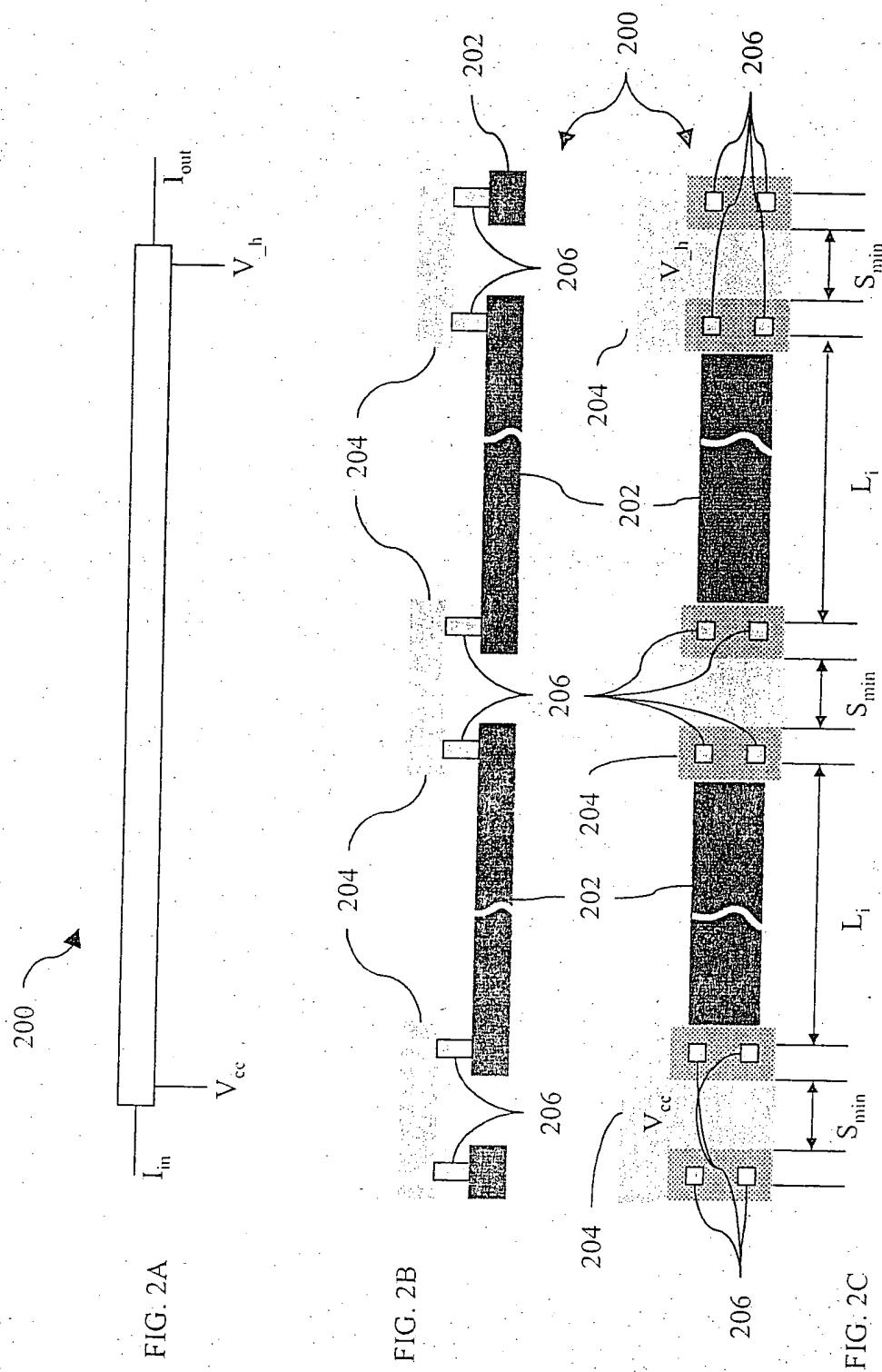


FIG. 1B



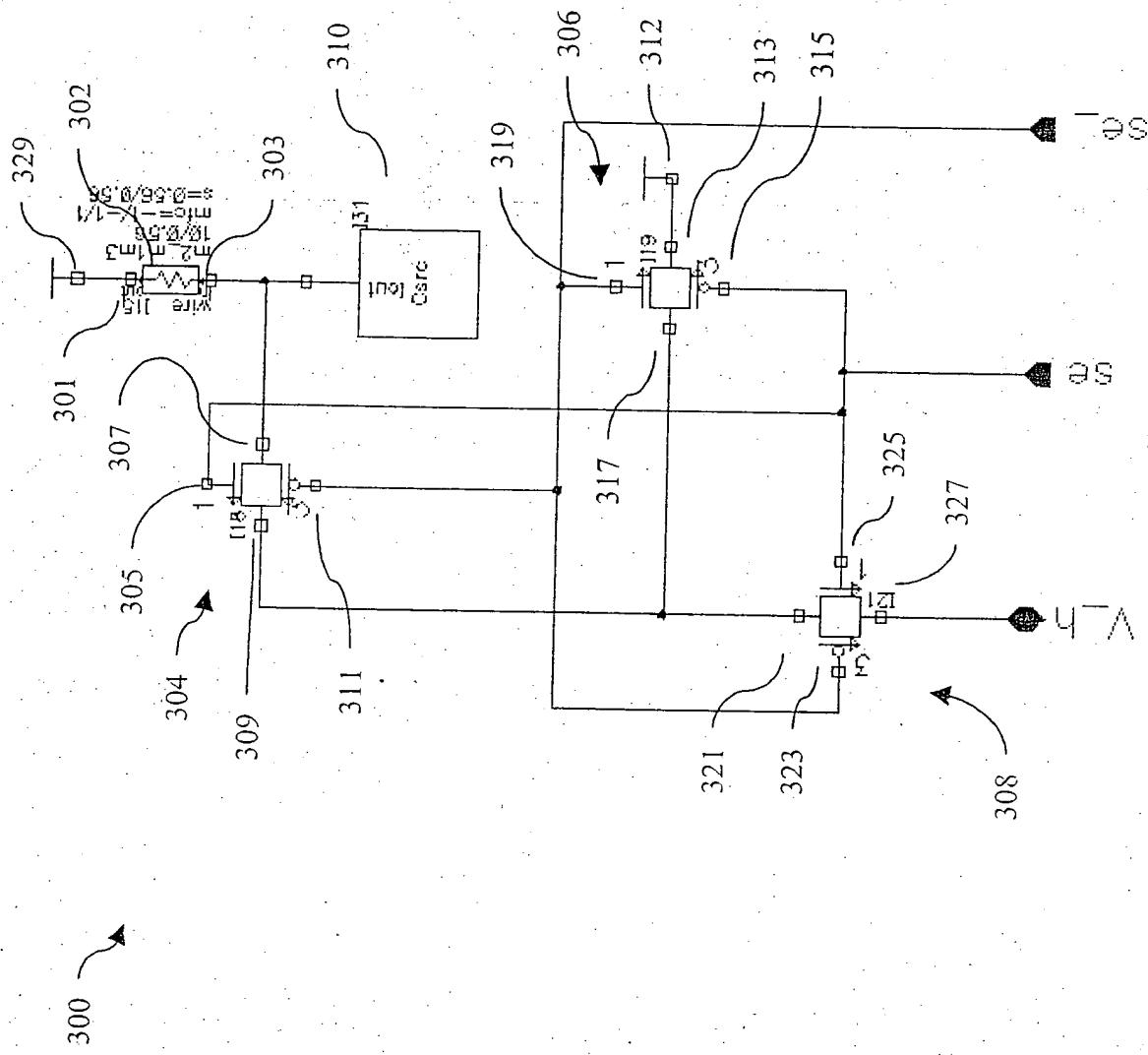


FIG. 3

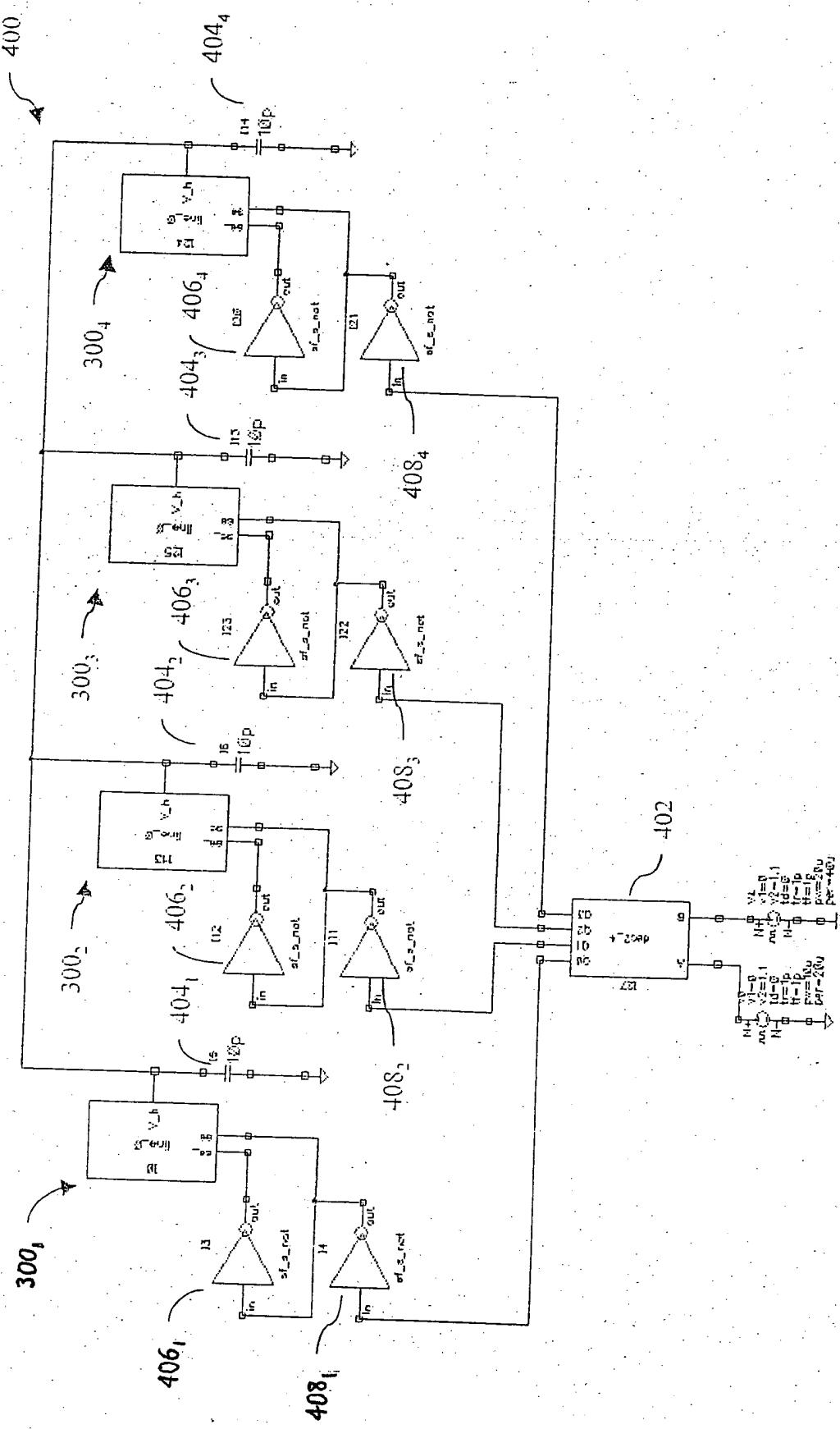


FIG. 4

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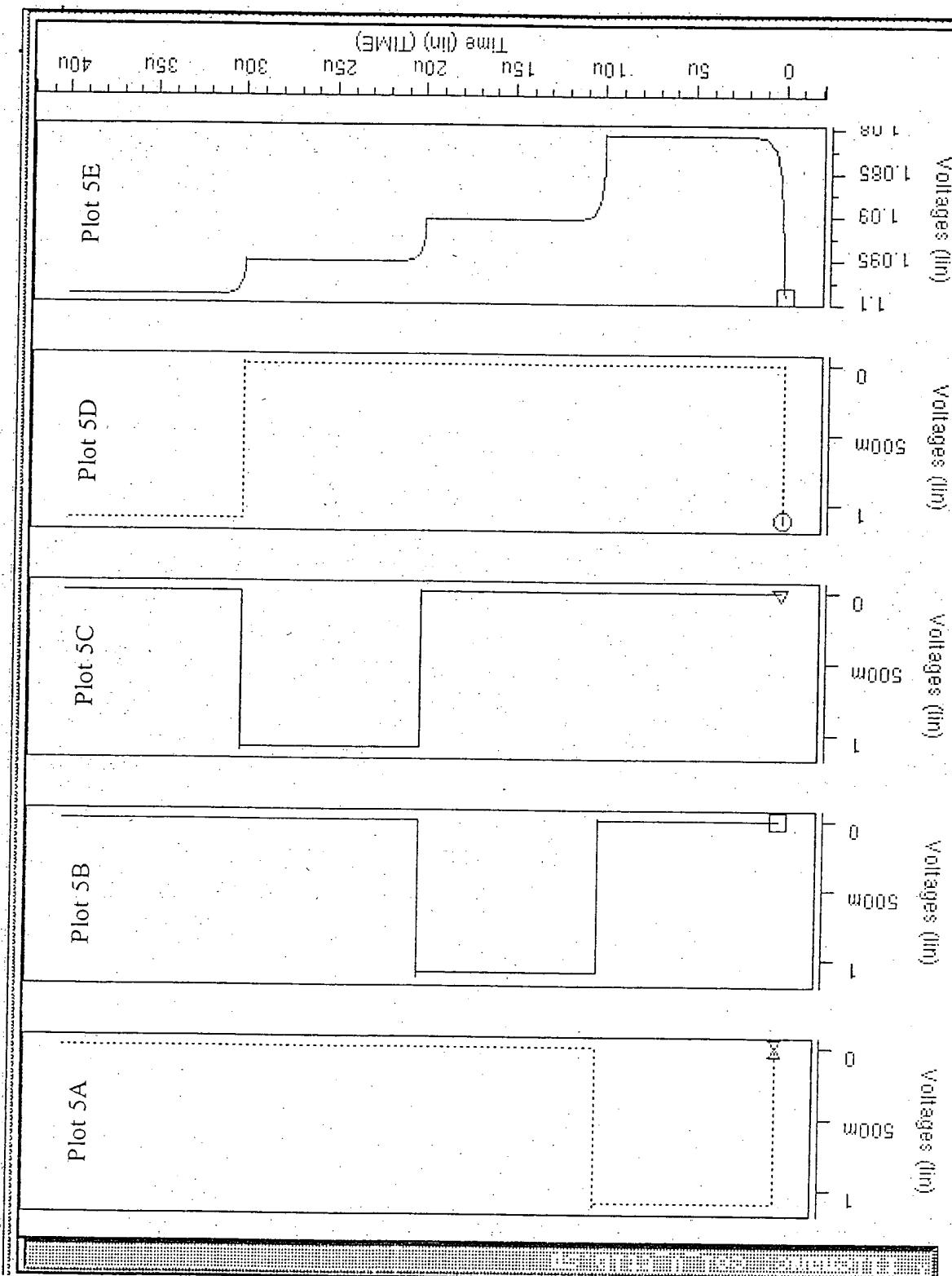


FIG. 5

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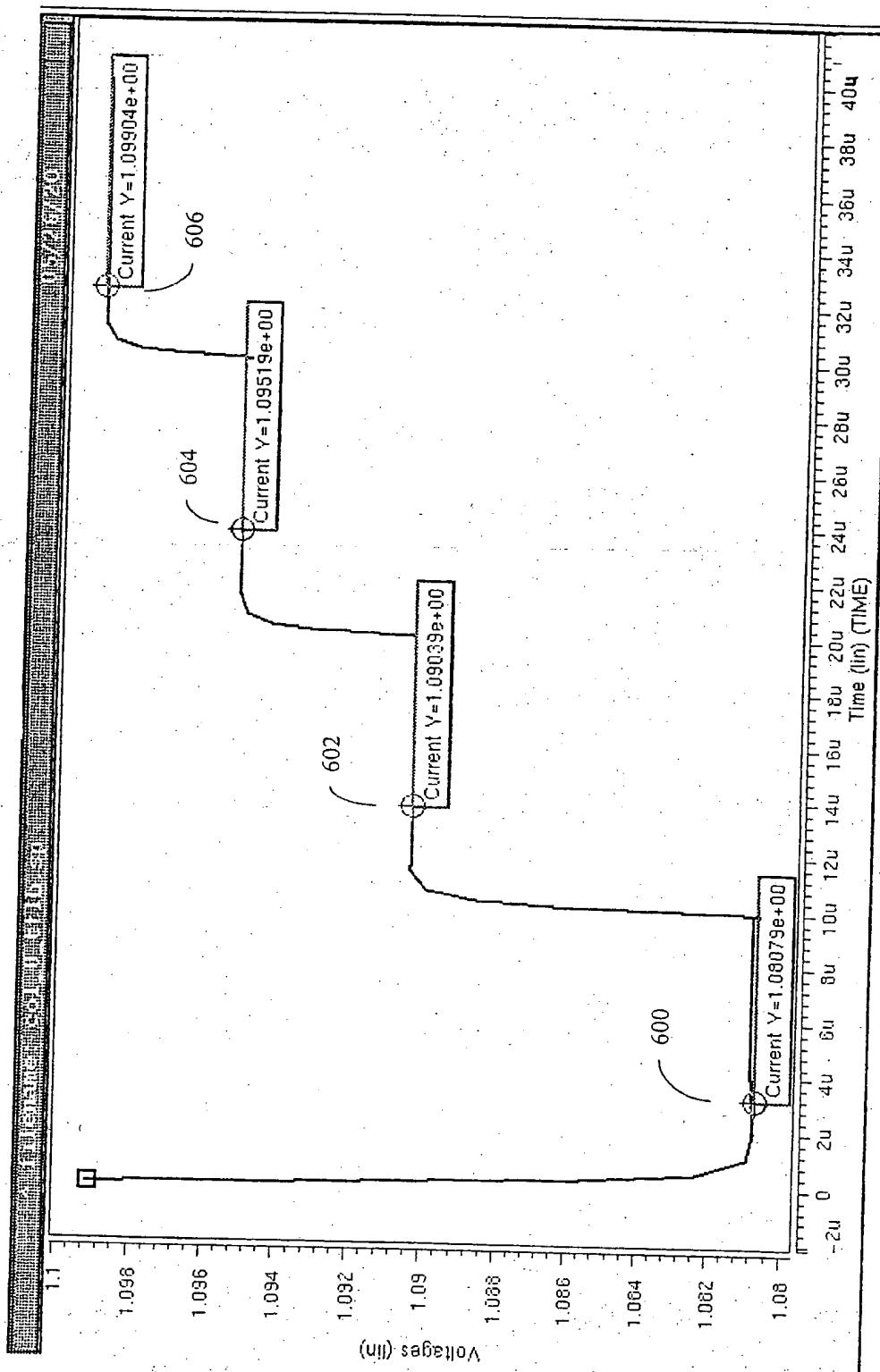


FIG. 6

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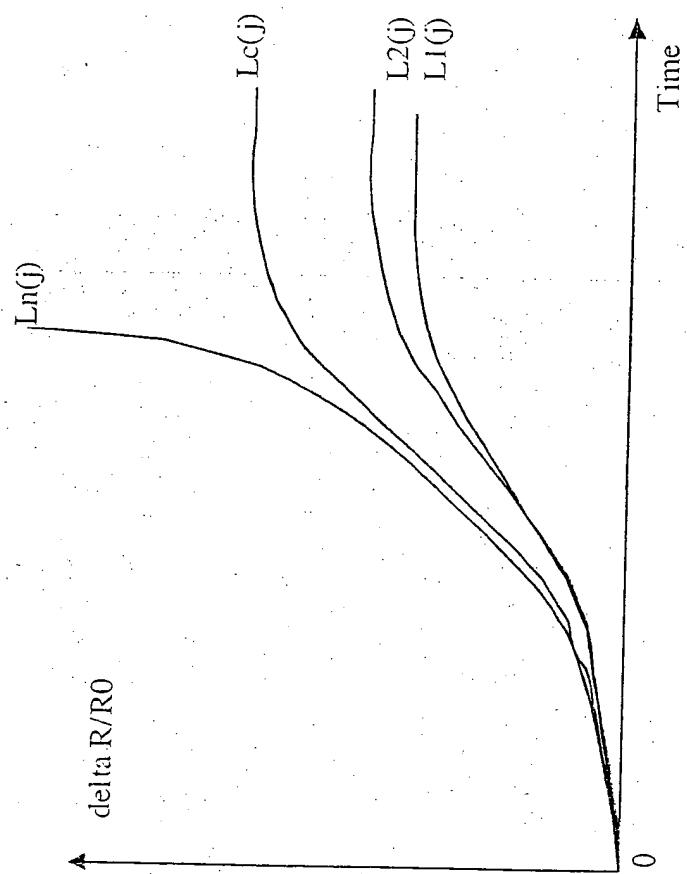


FIG. 7

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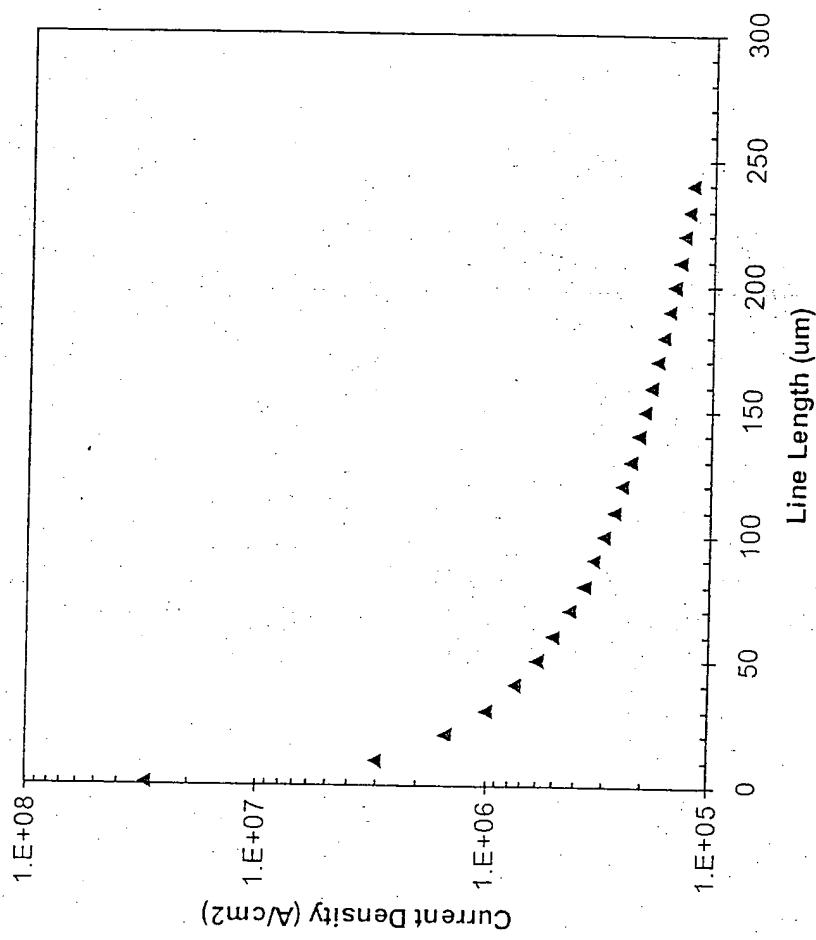


FIG. 8

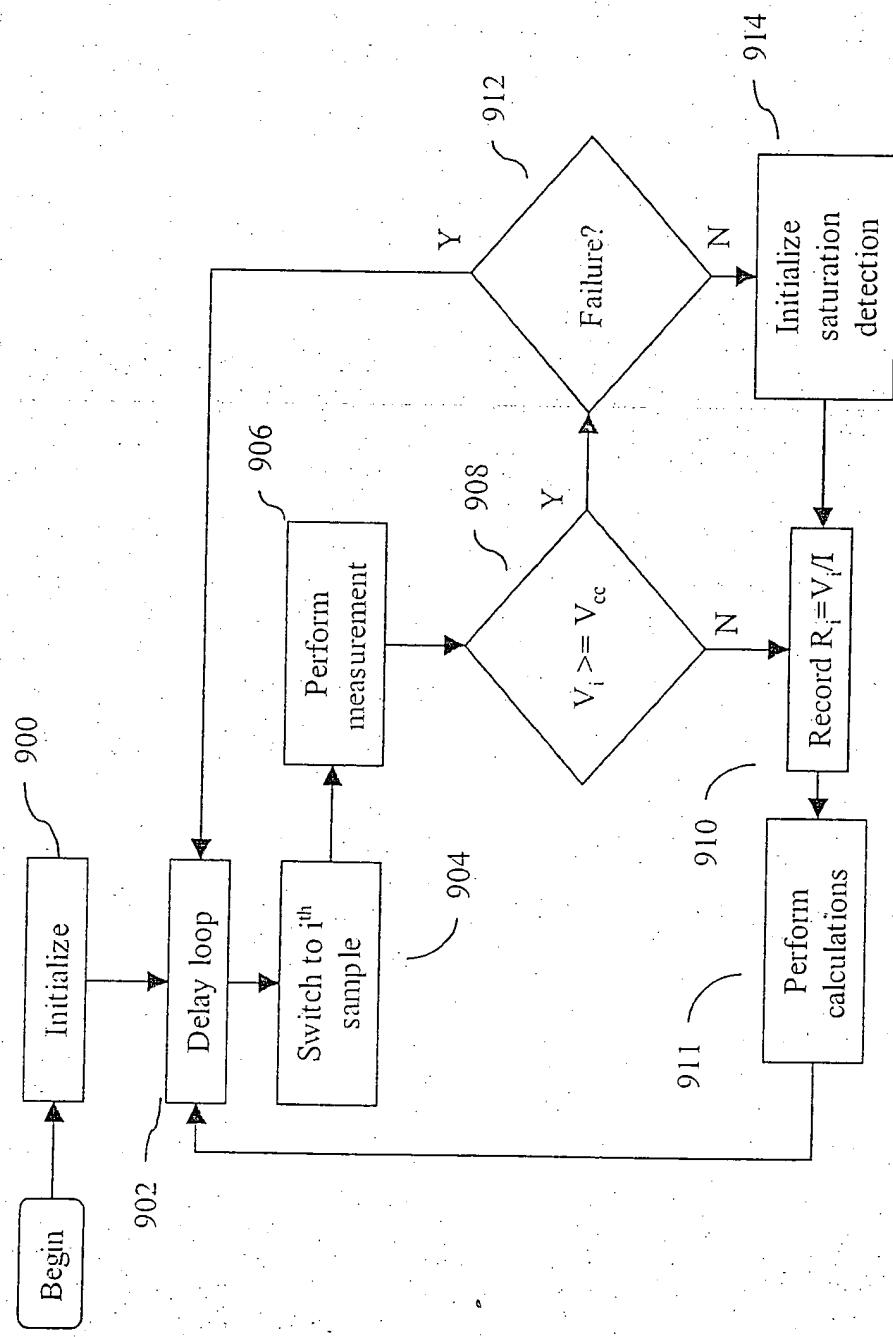


FIG. 9